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2nd June 2022

PCN-01549

Digi-Key Corporation  
701 Brooks Ave South  
Thief River Falls, Minnesota 56701

Subject: Additional testing and packaging site.

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

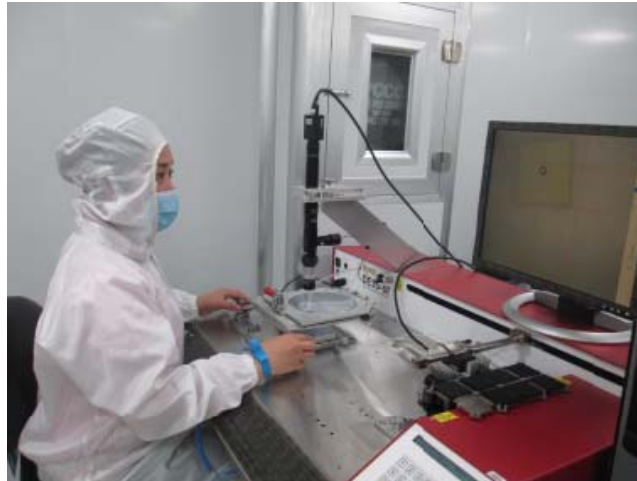
Sincerely

Tom Galluccio  
Director, Product Marketing  
[thomas.galluccio@macom.com](mailto:thomas.galluccio@macom.com)

**Appendix I**  
Affected part numbers

Part Number	Part type
M5X5536	Diode
MLP7130-11	Diode
MX51267-11	Diode
MX51316-11	Diode
MX51333-11	Diode
M3X1175	Capacitor
M3X3027	Capacitor

**Appendix II**  
The new testing and assembly facility



**Appendix III**  
Qualification process capability data

Two representative part numbers(MX51267-11 and MC2S022025-025) are tested and qualified in Year 2000 as below, and the rest parts in the pcn can be qualified by similarity to the representative parts as they have the same production process.

**1. Diode.**

**MX51267-11**

Test conditions: IR1max=10uA, under -1100V.

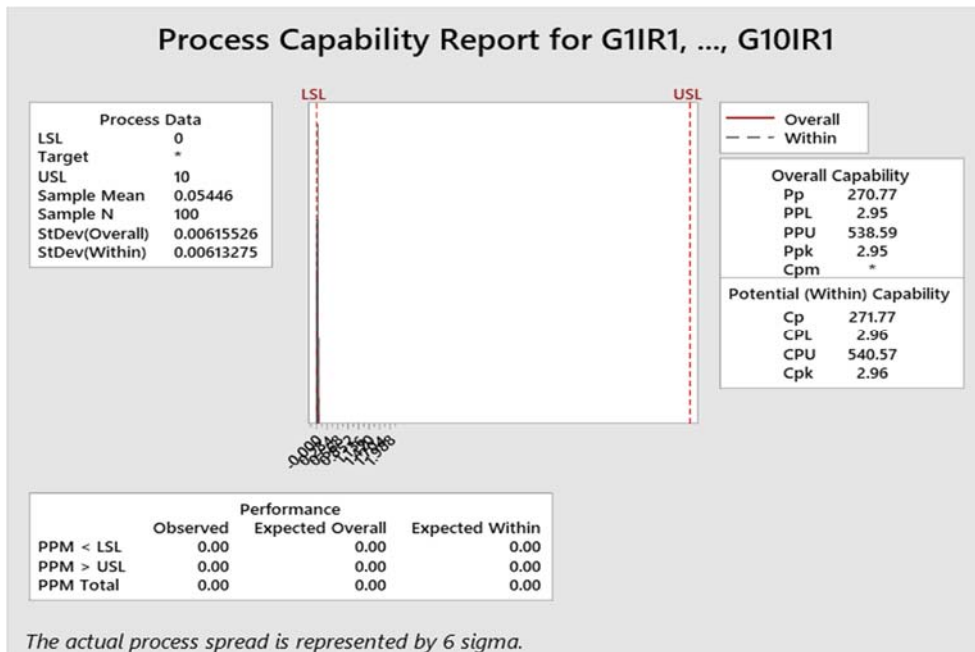
IR2max=0.05uA, under -1000V.

Cj1max=0.25pF, under -28V.

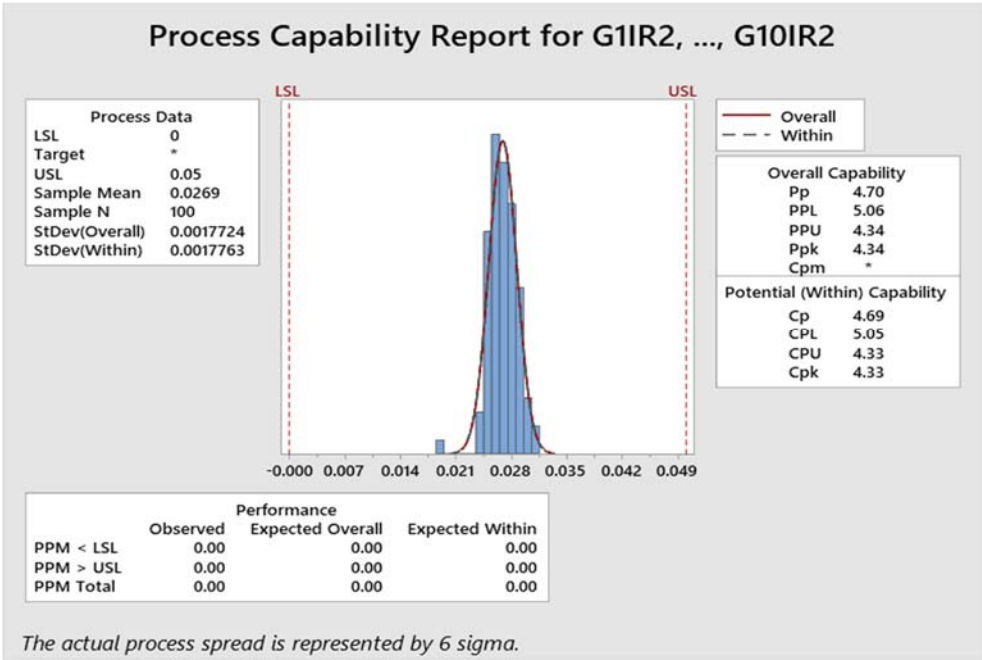
VF1max=1.25V, under 100mA.

Sample size=100,10 sub-groups.

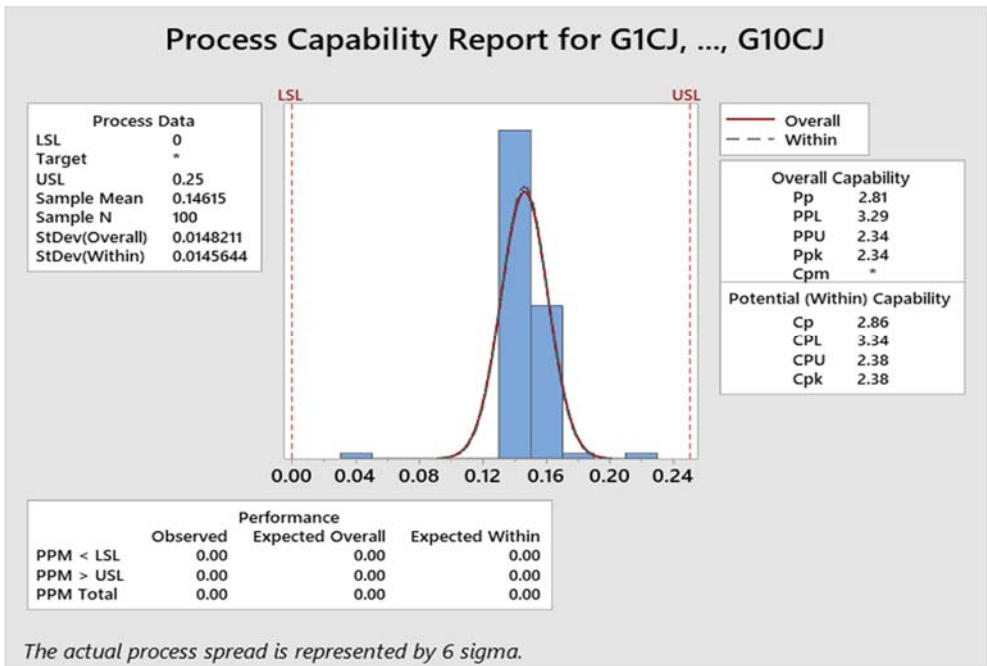
**IR1:**



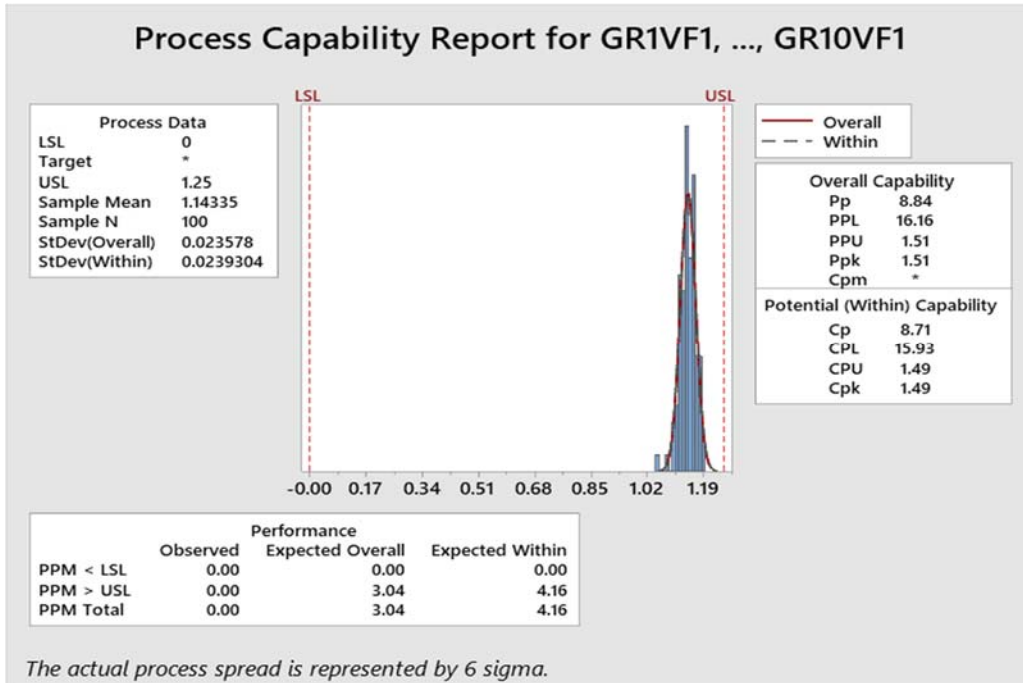
**IR2:**



**Cj1:**



**VF1:**



**2. Capacitor.**

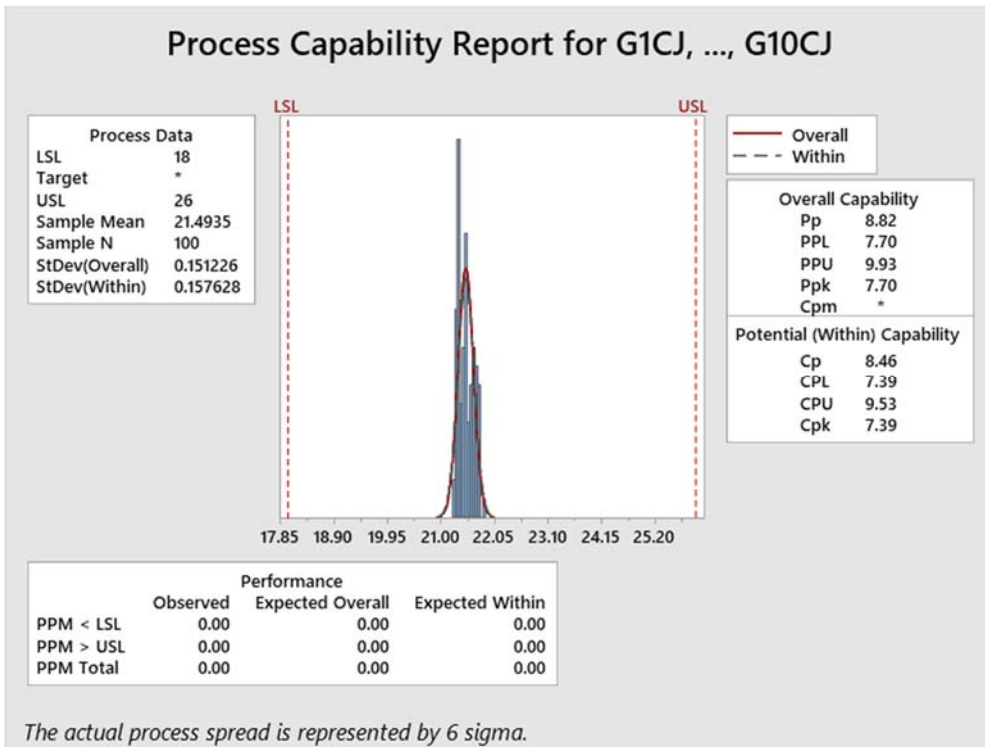
**MC2S022025-025**

Test conditions: Cj1min=18pF, Cj1max=26pF, under 0V.

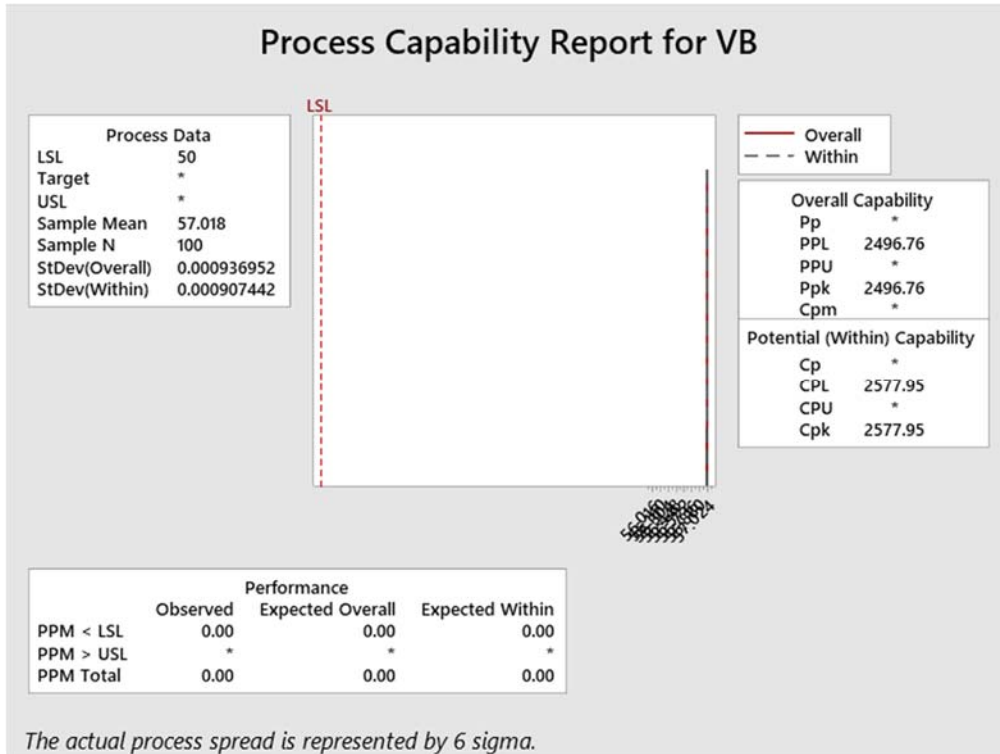
VBmin=50V, under -10uA.

Sample size=100,10 sub-groups.

**CJ1:**



**VB:**





**Appendix IV**  
Qualification Gage R&R testing data

**1. Diode test parameters**

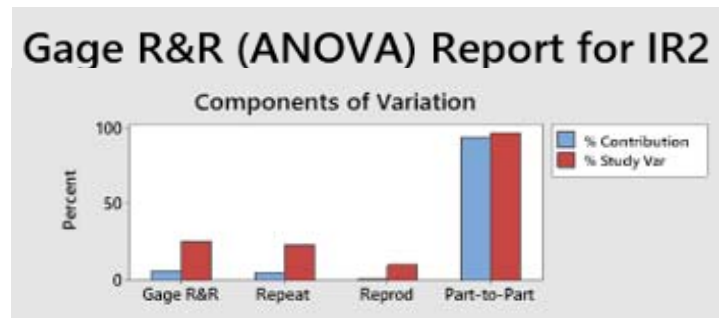
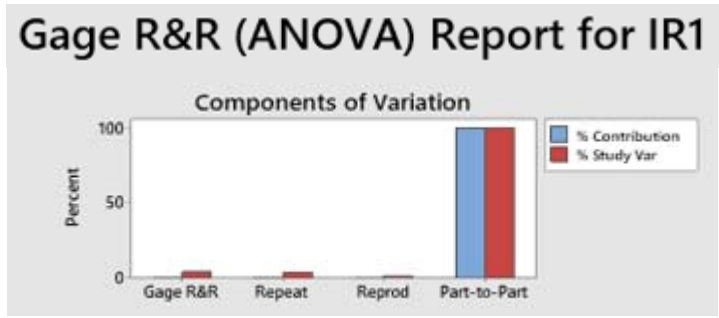
GR&R summary:

Specification:-

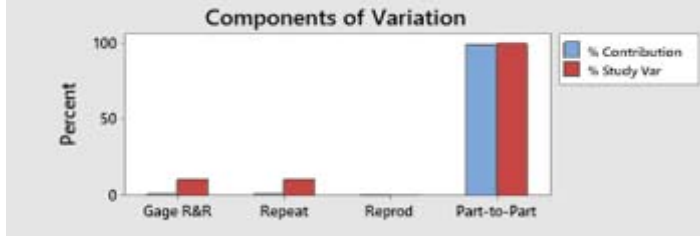
a) GR&R Contribution %  $\leq$ 10%

b) GR&R Variation %  $\leq$ 30%

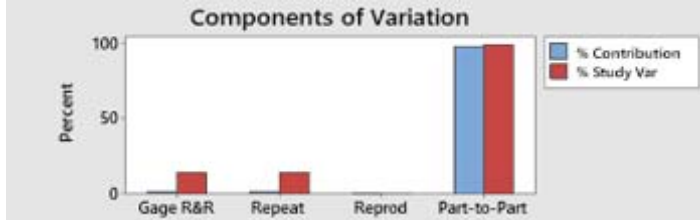
Parameter	GR&R Contribution %	GR&R Variation %	Result
IR1	0.21	4.57	PASS
IR2	6.62	25.72	PASS
Cj1	1.13	10.65	PASS
VF1	2.13	14.6	PASS



### Gage R&R (ANOVA) Report for Cj1



### Gage R&R (ANOVA) Report for VF1



## 2. Capacitor test parameters

GR&R summary:

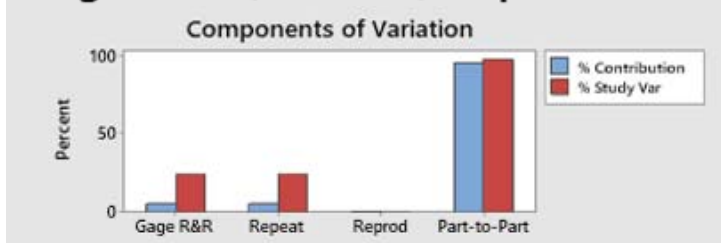
Specification:-

a) GR&R Contribution %  $\leq 10\%$

b) GR&R Variation %  $\leq 30\%$

Parameter	GR&R Contribution % GR&R	GR&R Variation% GR&R	Result
VB	5.69	23.85	PASS
Cj1	0	0.67	PASS

### Gage R&R (ANOVA) Report for Vb



## Gage R&R (ANOVA) Report for Cj1

